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FCC REPORT

Application No:	SZEM1803001945RG
Applicant:	Huawei Technologies Co., Ltd.
Manufacturer:	Huawei Technologies Co., Ltd.
Factory:	Huawei Technologies Co., Ltd.
Product Name:	Smart Phone
Model No.(EUT):	ALP-L29,ALP-L09
Trade Mark:	HUAWEI
FCC ID:	QISALP-LX9
Standards:	47 CFR FCC Part 2
	47 CFR FCC Part 22
	47 CFR FCC Part 27
Test Method:	FCC KDB 971168 D01 Power Meas License Digital Systems v03
	TIA-603-E 2016
Date of Receipt:	2018-03-11
Date of Test:	2018-03-11 to 2018-03-29
Date of Issue:	2018-05-02
Test Result:	PASS *

* In the configuration tested, the EUT detailed in this report complied with the standards specified above.



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2 Version

Revision Record				
Version	Chapter	Date	Modifier	Remark
01		2018-05-02		Original

Authorized for issue by:		
Tested By	Mike Mu	2018-05-02
	(Mike Hu) /Project Engineer	Date
Checked By	Jim Hug (Jim Huang) /Reviewer	2018-05-02



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3 Test Summary

3.1 Band 2(1850-1910 MHz paired with 1930-1990 MHz)

Test Item	FCC Rule No.	Requirements	Test Result	Verdict
Effective (Isotropic) Radiated Power Output Data	§2.1046, §24.232	EIRP ≤ 2 W	Section 1 of Appendix B	Pass
Peak-Average Ratio	§2.1046, §24.232	Limit≤13 dB	Section 2 of Appendix B	Pass
Modulation Characteristics	§2.1047	Digital modulation	Section 3 of Appendix B	Pass
Bandwidth	§2.1049	OBW: No limit. EBW: No limit.	Section 4 of Appendix B	Pass
Band Edges Compliance	§2.1051, §24.238	≤ -13 dBm/1%*EBW, in 1 MHz bands immediately outside and adjacent to the frequency block.	Section 5 of Appendix B	Pass
Spurious Emission at Antenna Terminals	§2.1051, §24.238	 ≤ -13 dBm/1 MHz, from 9 kHz to 10th harmonics but outside authorized operating frequency ranges. 	Section 6 of Appendix B	Pass
Field Strength of Spurious Radiation	§2.1053, §24.238	≤ -13 dBm/1 MHz.	Section 7 of Appendix B	Pass
Frequency Stability	§2.1055, §24.235	≤ ±2.5 ppm.	Section 8 of Appendix B	Pass
NOTE:For the verdict, the "N/A" denotes "not applicable", the "N/T" denotes "not tested".				



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3.2 Band 7 (2500-2570 MHz paired with 2620-2690 MHz)

Effective (isotropic) Radiated Power Output Data§2.1046, §27.50(n)EIRP ≤ 2WSection 1 of Appendix BPassPeak-Average Ratio§27.50(a)Limits13 dBSection 2 of Appendix BPassModulation Characteristics§2.1047Digital modulationSection 3 of Appendix BPassBandwidth§2.1049OBW: No limit. EBW: No limit.Section 4 of Appendix BPassBandwidth§2.1049OBW: No limit. EBW: No limit.Section 4 of Appendix BPassBand Edges Compliance§2.1051, §27.53(m4)2000 Compliance 2000 ComplianceSection 5 of Appendix BPassSpurious Emission at Antema Terminals§2.1051, §27.53(m)2000 Compliance 2000 ComplianceSection 6 of Appendix BPassField Strength of Spurious Radiation§2.1053, §27.53(m)2000 Compliance 2000 ComplianceSection 7 of Appendix BPassField Strength of Spurious Radiation§2.1053, §27.53(m)2000 Compliance 2000 ComplianceSection 7 of Appendix BPassField Strength of Spurious Radiation§2.1053, §27.53(m)2000 Compliance 2000 ComplianceSection 7 of Appendix BPassFrequency Stability Spurious Radiation§2.1053, §27.53(m)2000 Compliance 2000 ComplianceSection 8 of Appendix BPassFrequency Stability Spurious Radiation§2.1055, §27.53(m)Within authorized bands of Appendix BSection 8 of Appendix BPassFrequency Stability Spurious Radiation<	Test Item	FCC Rule No.	Requirements	Test Result	Verdict
Ratio\$27.50(a)Limits is usAppendix BPassModulation Characteristics\$2.1047Digital modulationSection 3 of Appendix BPassBandwidth\$2.1049OBW: No limit. EBW: No limit.Section 4 of Appendix BPassBandwidth\$2.1049OBW: No limit. EBW: No limit.Section 4 of Appendix BPassBandwidth\$2.1049OBW: No limit. EBW: No limit.Section 4 of Appendix BPassBand Edges Compliance\$2.1051, \$27.53(m4)\$2.1051, \$2.1051, \$2.753(m4)Section 5 of \$2.1051, \$2.1052, \$2.1052, \$2.1052,Section 6 of Appendix BPassField Strength of Spurious Radiation\$2.1053, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, \$2.1055, <br< td=""><td>Radiated Power</td><td></td><td>EIRP ≤ 2W</td><td></td><td>Pass</td></br<>	Radiated Power		EIRP ≤ 2W		Pass
Characteristics\$2.1047Digital modulationAppendix BPassBandwidth\$2.1049OBW: No limit.Section 4 of Appendix BPassBandwidth\$2.1049ComplianceSection 5 of \$2.1051, \$27.53(m4)Section 5 of \$2.1051, \$27.53(m4)Section 5 of \$2.1051, \$27.53(m4)Section 5 of \$2.1051, \$27.53(m4)Section 6 of \$2.1051, \$27.53(m4)PassSpurious Emission at Antenna Terminals\$2.1051, \$27.53(m)Section 6 of \$2.1051, \$27.53(m4)Section 6 of \$2.1051, \$27.53(m4)Section 7 of Appendix BPassField Strength of Spurious Radiation\$2.1053, \$27.53(m)\$2.1053, \$27.53(m4)Section 7 of \$2.1056, \$2.1056, \$2.1056, \$2.1056, \$2.1056, \$2.1057, <br< td=""><td></td><td>§27.50(a)</td><td>Limit≤13 dB</td><td></td><td>Pass</td></br<>		§27.50(a)	Limit≤13 dB		Pass
Bandwidth§2.1049EBW: No limit.Appendix BPassBand Edges Compliance§2.1051, §27.53(m4)20:5000 1000 10000 100000 100000 100000 100000 1000000		§2.1047	Digital modulation		Pass
Band Edges Compliance §2.1051, §27.53(m4) §2.1051, §27.53(m4) Section 5 of solution Section 5 of Appendix B Pass Spurious Emission at Antenna Terminals §2.1051, §27.53(m) \$2.1051, §27.53(m) Section 6 of solution Section 6 of Appendix B Pass Field Strength of Spurious Radiation §2.1053, §27.53(m) \$2.1053, §27.53(m) Section 7 of Solution Section 7 of Appendix B Pass Frequency Stability \$2.1055, §27.54 Section 5 of Appendix B Section 6 of Appendix B Pass	Bandwidth	§2.1049			Pass
Spurious Emission at Antenna Terminals§2.1051, §27.53(m)Section 6 of Appendix BPassField Strength of Spurious Radiation§2.1053, §27.53(m)Section 6 of 1 MHz 9 kHz 9 kHz 			-10 dBm Edge -10 dBm -10 dBm 13 dBm -13 dBm -14 dBm -14 dBm -14 dBm -15 SMHz 4M 1M ₂ I^{M} 4 MHz (X-4) MHz RBW 22%*EBW RBW 22%*EBW -10 dBm -10		Pass
Field Strength of Spurious Radiation§2.1053, §27.53(m)Edge -25dBm/ 1 MHzSection 7 of Appendix BPassFrequency Stability§2.1055, §27.54Within authorized bands of operation/frequency block.Section 8 of Appendix BPass	at Antenna		9 kHz 9 5 MHz XMHz 10 th harmonics X=Max {6MHz, EBW}		Pass
Frequency Stability §27.54 operation/frequency block. Appendix B Pass			Edge -25 dBm/ 1 MHz // 1 MHz		Pass
		§27.54	operation/frequency block.	Appendix B	Pass



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3.3 BRS&EBS Band38 (2570-2620 MHz paired with 2570-2620 MHz)

Test Item	FCC Rule No.	Requirements	Test Result	Verdict
Effective (Isotropic) Radiated Power Output Data	§2.1046, §27.50(h)	EIRP ≤ 2W	Section 1 of Appendix B	Pass
Peak-Average Ratio	§27.50(a)	FCC: Limit≤13 dB	Section 2 of Appendix B	Pass
Modulation Characteristics	§2.1047	Digital modulation	Section 3 of Appendix B	Pass
Bandwidth	§2.1049	OBW: No limit. EBW: No limit.	Section 4 of Appendix B	Pass
Band Edges Compliance	§2.1051, §27.53(m)	2%*EBW Channel 2%*EBW -10dBm Edge -10dBm -10dBm 1m 1m 1m 5.5MHz 4M IM RBW ≥2%*EBW RBW ≥2%*EBW X=Max {6MHz, EBW}	Section 5 of Appendix B	Pass
Spurious Emission at Antenna Terminals	§2.1051, §27.53(m)	P kHz %5 MHz X MHz 10 th harmonics X=Max {6MHz, EBW}	Section 6 of Appendix B	Pass
Field Strength of Spurious Radiation	§2.1053, §27.53(m)	P kHz 9 5 MHz XMHz 10 th harmonics X=Max {6MHz, EBW}	Section 7 of Appendix B	Pass
Frequency Stability §27.54 operation/frequency block. Appendix		Section 8 of Appendix B	Pass	
NOTE:For the verdict, the "N/A" denotes "not applicable", the "N/T" denotes "not tested".				



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3.4 Band41 (2545-2655 MHz paired with 2545-2655 MHz)

Test Item	FCC Rule No.	Requirements	Test Result	Verdict
Effective (Isotropic) Radiated Power Output Data	§2.1046, §27.50(h)	EIRP ≤ 2W	Section 1 of Appendix B	Pass
Peak-Average Ratio	§27.50(a)	FCC:Limit≤13 dB	Section 2 of Appendix B	Pass
Modulation Characteristics	§2.1047	Digital modulation	Section 3 of Appendix B	Pass
Bandwidth	§2.1049	OBW: No limit. EBW: No limit.	Section 4 of Appendix B	Pass
Band Edges Compliance	§2.1051, §27.53(m)	2%*EBW Channel 2%*EBW -10dBm Edge -10dBm -10dBm 1 13 dBm 1 5.5MHz 4M 1 RBW ≥2%*EBW RBW ≥2%*EBW X=Max {6MHz, EBW}	Section 5 of Appendix B	Pass
Spurious Emission at Antenna Terminals	§2.1051, §27.53(m)	Channel Edge -25 dBm/ 1 MHz 9 kHz 9 kHz X=Max {6MHz, EBW}	Section 6 of Appendix B	Pass
Field Strength of Spurious Radiation	§2.1053, §27.53(m)	P kHz 9 5 MHz XMHz 10 th harmonics X=Max {6MHz, EBW}	Section 7 of Appendix B	Pass
Frequency Stability	§2.1055, §27.54	Within authorized bands of operation/frequency block.Section 8 of Appendix B		Pass
NOTE:For the verdict, the "N/A" denotes "not applicable", the "N/T" denotes "not tested".				



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4 General Information

4.1 Client Information

Applicant:	Huawei Technologies Co., Ltd.
Address of Applicant:	Administration Building, Headquarters of Huawei Technologies Co., Ltd., Bantian, Longgang District, Shenzhen, 518129, P.R.C
Manufacturer:	Huawei Technologies Co., Ltd.
Address of Manufacturer:	Administration Building, Headquarters of Huawei Technologies Co., Ltd., Bantian, Longgang District, Shenzhen, 518129, P.R.C
Factory:	Huawei Technologies Co., Ltd.
Address of Factory:	Administration Building, Headquarters of Huawei Technologies Co., Ltd., Bantian, Longgang District, Shenzhen, 518129, P.R.C

4.2 General Description of EUT

Product Name:	Smart Phone
Model No.:	ALP-L29, ALP-L09
Trade Mark:	HUAWEI
Sample Type:	Portable production
Antenna Type:	Internal
	LTE B2: -0.4 dBi;
Antenna Gain:	LTE B7: 1 dBi;
Antenna Gain.	LTE B38: 0.5 dBi;
	LTE B41: 0.5 dBi

The difference between ALP-L29 & ALP -L09 is as bellow:

Model	ALP-L29	ALP -L09
Brand	the same	the same
Frequency	the same	the same
SIM Card	Dual SIM	Single SIM
Hardware Version	the same	the same
Software Version	Different	Different
Dimensions	the same	the same
Appearance	the same	the same
main antenna	the same	the same
BT/Wi-Fi antenna	the same	the same
div antenna	the same	the same

Note:

We did all the test on ALP-L29, and all the test data of ALP -L09 can refer to ALP -L29.

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4.3 Test Mode

Test Mode	Test Modes Description
LTE/TM1	LTE system, QPSK modulation
LTE/TM2	LTE system, 16QAM modulation
LTE/TM3	LTE system, 64QAM modulation

		E-UTRA CA	E-UTRA CA configuration / Bandwidth combination set						
		Component	carriers in ord	er of increasin	ig carrier frequ	iency	Maximum		
E-UTRA CA configuration	Uplink CA configurations (NOTE 3)	Channel bandwidths for carrier [MHz]	Channel bandwidths for carrier [MHz]	Channel bandwidths for carrier [MHz]	Channel bandwidths for carrier [MHz]	Channel bandwidths for carrier [MHz]	Maximum aggregated bandwidth [MHz]		
		5	20						
CA_2C	CA_2C	10	15,20				40		
UA_20	UA_20	15	10,15,20				40		
		20	5,10,15,20						
		15	15						
		20	20						
		10	20						
CA_7C	CA_7C	15	15, 20				40		
		20	10, 15, 20						
		15	10, 15						
		20	15, 20						
CA_38C	CA_38C	15	15				40		
UA_360	UA_360	20	20				40		
		10	20						
		15	15, 20						
		20	10, 15, 20						
		5, 10	20						
		15	15, 20						
CA_41C	CA_41C	20	5, 10, 15, 20				40		
		10	15, 20						
		15	10, 15, 20						
		20	10, 15, 20]		
		10	20						
		20	20				<u> </u>		

NOTE1: E-UTRA CA configurations and bandwidth combination sets defined for intra-band contiguous CA)

(Release 14)

NOTE2: The test mode(s) are selected according to relevant radio technology specifications.



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4.4 Test Environment

Environment Parameter	Selected Values During Tests				
Relative Humidity		52%			
Atmospheric Pressure:	1015MPa				
Temperature	TN 25 ℃				
	VL	3.6V			
Voltage :	VN	3.82V			
	VH	4.35V			

NOTE: VL= lower extreme test voltage

VN= nominal voltage

VH= upper extreme test voltage

TN= normal temperature



4.5.1

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch

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4.5 Test Frequency

4.5.1	•			A-2.10	Stilley	uencies		/A_20			
Range	CC-Combo / NRB_agg			CC1 Note1					CC2 Note1		
naliye	[RB]	BW [RB]	N _{UL}	f _{∪∟} [MHz]	N _{DL}	f _{DL} [MHz]	BW [RB]	N _{UL}	f _{∪∟} [MHz]	N _{DL}	f _{DL} [MHz]
	25+100	25	18633	1853.3	633	1933.3	100	18750	1865	750	1945
	25+100	100	18700	1860	700	1940	25	18817	1871.7	817	1951.7
	50+75	50	18653	1855.3	653	1935.3	75	18773	1867.3	773	1947.3
	50+75	75	18675	1857.5	675	1937.5	50	18795	1869.5	795	1949.5
Low	50+100	50	18655	1855.5	655	1935.5	100	18799	1869.9	799	1949.9
LOW	50+100	100	18700	1860	700	1940	50	18844	1874.4	844	1954.4
	75+75	75	18675	1857.5	675	1937.5	75	18825	1872.5	825	1952.5
	75+100	75	18678	1857.8	678	1937.8	100	18849	1874.9	849	1954.9
	75+100	100	18700	1860	700	1940	75	18871	1877.1	871	1957.1
	100+100	100	18700	1860	700	1940	100	18898	1879.8	898	1959.8
	25+100	25	18808	1870.8	808	1950.8	100	18925	1882.5	925	1962.5
		100	18875	1877.5	875	1957.5	25	18992	1889.2	992	1969.2
	50+75	50	18829	1872.9	829	1952.9	75	18949	1884.9	949	1964.9
		75	18851	1875.1	851	1955.1	50	18971	1887.1	971	1967.1
Mid	50+100	50	18806	1870.6	806	1950.6	100	18950	1885	950	1965
INITO		100	18851	1875.1	851	1955.1	50	18995	1889.5	995	1969.5
	75+75	75	18825	1872.5	825	1952.5	75	18975	1887.5	975	1967.5
	75,100	75	18803	1870.3	803	1950.3	100	18974	1887.4	974	1967.4
	75+100	100	18826	1872.6	826	1952.6	75	18997	1889.7	997	1969.7
	100+100	100	18801	1870.1	801	1950.1	100	18999	1889.9	999	1969.9
	05,100	25	18983	1888.3	983	1968.3	100	19100	1900	1100	1980
	25+100	100	19050	1895	1050	1975	25	19167	1906.7	1167	1986.7
	E0 . 7E	50	19005	1890.5	1005	1970.5	75	19125	1902.5	1125	1982.5
	50+75	75	19027	1892.7	1027	1972.7	50	19147	1904.7	1147	1984.7
High	50.100	50	18956	1885.6	956	1965.6	100	19100	1900	1100	1980
	50+100	100	19001	1890.1	1001	1970.1	50	19145	1904.5	1145	1984.5
	75+75	75	18975	1887.5	975	1967.5	75	19125	1902.5	1125	1982.5
	75.100	75	18929	1882.9	929	1962.9	100	19100	1900	1100	1980
	75+100	100	18951	1885.1	951	1965.1	75	19122	1902.2	1122	1982.2
	100+100	100	18902	1880.2	902	1960.2	100	19100	1900	1100	1980
Note 1:	Carriers in inc	reasing f	frequency	order.							

Table 4.3.1.1.2A-2: Test frequencies for CA_2C



4.5.2

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch

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Dongo	CC-Combo /			CC1 Note1			CC2 Note1				
Range	NRB_agg [RB]	BW [RB]	N _{UL}	f _{∪∟} [MHz]	N _{DL}	f _{DL} [MHz]	BW [RB]	N _{UL}	f _{∪∟} [MHz]	N _{DL}	f _{DL} [MHz]
	50+100	50	20805	2505.5	2805	2625.5	100	20949	2519.9	2949	2639.9
	50+100	100	20850	2510	2850	2630	50	20994	2524.4	2994	2644.4
Low	75+75	75	20825	2507.5	2825	2627.5	75	20975	2522.5	2975	2642.5
Low	75,100	75	20828	2507.8	2828	2627.8	100	20999	2524.9	2999	2644.9
	75+100	100	20850	2510	2850	2630	75	21021	2527.1	3021	2647.1
	100+100	100	20850	2510	2850	2630	100	21048	2529.8	3048	2649.8
	50+100	50	21006	2525.6	3006	2645.6	100	21150	2540	3150	2660
		100	21051	2530.1	3051	2650.1	50	21195	2544.5	3195	2664.5
Mid	75+75	75	21025	2527.5	3025	2647.5	75	21175	2542.5	3175	2662.5
IVIIC	75,100	75	21003	2525.3	3003	2645.3	100	21174	2542.4	3174	2662.4
	75+100	100	21026	2527.6	3026	2647.6	75	21197	2544.7	3197	2664.7
	100+100	100	21001	2525.1	3001	2645.1	100	21199	2544.9	3199	2664.9
	E0.100	50	21206	2545.6	3206	2665.6	100	21350	2560	3350	2680
	50+100	100	21251	2550.1	3251	2670.1	50	21395	2564.5	3395	2684.5
Lliab	75+75	75	21225	2547.5	3225	2667.5	75	21375	2562.5	3375	2682.5
High	75,100	75	21179	2542.9	3179	2662.9	100	21350	2560	3350	2680
	75+100	100	21201	2545.1	3201	2665.1	75	21372	2562.2	3372	2682.2
	100+100	100	21152	2540.2	3152	2660.2	100	21350	2560	3350	2680
Note 1:	Carriers in inc	reasing f	requency	/ order.							

Table 4.3.1.1.1A-1: Test frequencies for CA_7C

4.5.3

Table 4.3.1.2.6A-1: Test frequencies for CA_38C

Dongo	CC-Combo /		CC1 Note1			CC2 Note1	
Range	NRB_agg [RB]	BW [RB]	N _{UL/DL}	f _{∪L/DL} [MHz]	BW [RB]	N _{UL/DL}	f _{∪L/DL} [MHz]
Low	75+75	75	37825	2577.5	75	37975	2592.5
Low	100+100	100	37850	2580	100	38048	2599.8
Mid	75+75	75	37925	2587.5	75	38075	2602.5
IVIIO	100+100	100	37901	2585.1	100	38099	2604.9
Lliab	75+75	75	38025	2597.5	75	38175	2612.5
High	100+100	100	37952	2590.2	100	38150	2610
Note 1: Carriers in increasing frequency order.							



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Denne	CC-Combo /		CC1 Note1			CC2 Note1	
Range	NRB_agg [RB]	BW [RB]	N _{UL/DL}	f _{∪L/DL} [MHz]	BW [RB]	N _{UL/DL}	f _{UL/DL} [MHz]
	25+100	25	40165	2547.5	100	40282	2559.2
	25+100	100	40240	2555	25	40357	2566.7
	50+100	50	40190	2550	100	40334	2564.4
Low	50+100	100	40240	2555	50	40384	2569.4
Low	75+75	75	40215	2552.5	75	40365	2567.5
	75,100	75	40215	2552.5	100	40386	2569.6
	75+100	100	40240	2555	75	40411	2572.1
	100+100	100	40240	2555	100	40438	2574.8
	25+100	25	40598	2590.8	100	40715	2602.5
		100	40665	2597.5	25	40782	2609.2
	50+100 -	50	40596	2590.6	100	40740	2565.0
Mid		100	40641	2595.1	50	40785	2609.5
Mid	75+75	75	40615	2592.5	75	40765	2607.5
	75,100	75	40593	2590.3	100	40764	2607.4
	75+100	100	40616	2592.6	75	40787	2609.7
	100+100	100	40591	2590.1	100	40789	2609.9
	05 100	25	41023	2633.3	100	41140	2645
	25+100	100	41098	2640.8	25	41215	2652.5
	50,400	50	40996	2630.6	100	41140	2645
Liberte	50+100	100	41046	2635.6	50	41190	2650
High	75+75	75	41014	2632.5	75	41165	2647.5
		75	40969	2627.9	100	41140	2645
	75+100	100	40994	2630.4	75	41165	2647.5
	100+100	100	40942	2625.2	100	41140	2645
Note 1:	Carriers in increa						

Table 4.3.1.2.9A-1: Test frequencies for CA 41C



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4.6 Test Location

All tests were performed at:

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen Branch

No. 1 Workshop, M-10, Middle Section, Science & Technology Park, Shenzhen, Guangdong, China. 518057.

Tel: +86 755 2601 2053 Fax: +86 755 2671 0594

No tests were sub-contracted.

4.7 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

CNAS (No. CNAS L2929)

CNAS has accredited SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC Lab to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration Laboratories (CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence in the field of testing.

A2LA (Certificate No. 3816.01)

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory is accredited by the American Association for Laboratory Accreditation(A2LA). Certificate No. 3816.01.

• VCCI

The 10m Semi-anechoic chamber and Shielded Room of SGS-CSTC Standards Technical Services Co., Ltd. have been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-823, R-4188, T-1153 and C-2383 respectively.

• FCC – Designation Number: CN1178

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory has been recognized as an accredited testing laboratory.

Designation Number: CN1178. Test Firm Registration Number: 406779.

Industry Canada (IC)

Two 3m Semi-anechoic chambers and the 10m Semi-anechoic chamber of SGS-CSTC Standards

Technical Services Co., Ltd. Shenzhen Branch EMC Lab have been registered by Certification and

Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 4620C-1, 4620C-2, 4620C-3.

4.8 Deviation from Standards

None.

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4.9 Abnormalities from Standard Conditions

None.

4.10Other Information Requested by the Customer

None.

4.11 Technical Specification

Characteristics	Description					
Radio System Type	LTE_CA					
		Transmission (TX): 1850 to 1910 MHz				
	LTE CA_2C	Receiving (RX):1970 to 1990 MHz				
		Transmission (TX): 2500 to 2570 MHz				
Supported Erequency Panga	LTE CA_7C	Receiving (RX):2620 to 2690 MHz				
Supported Frequency Range	LTE CA 38C	Transmission (TX): 2570 to 2620 MHz				
	LIE CA_300	Receiving (RX): 2570 to 2620 MHz				
	LTE CA 41C	Transmission (TX): 2545 to 2655 MHz				
		Receiving (RX): 2545 to 2655 MHz				
	LTE CA_2C: 24dBm					
Target TX Output Power	LTE CA_7C: 23.5dBm					
Targer TX Output Tower	LTE CA_38C: 24dBm					
	LTE CA_41C: 24dBm					
	LTE CA_2C	⊠25+100;⊠50+75; ⊠50+100; ⊠75+75; ⊠75+100, ⊠100+100				
	LTE CA 7C	⊠50+100; ⊠75+50; ⊠75+75, ⊠75+100				
Supported Channel Bandwidth		⊠100+100				
	LTE CA_38C	⊠75+75; ⊠100+100;				
	LTE CA_41C	⊠25+100;⊠50+75; ⊠50+100; ⊠75+75; ⊠75+100, ⊠100+100				

Characteristics		Description			
		100RB+25RB	22M9G7D;22M9W7D; 22M9W7D		
Designation of Emissions	LTE CA_2C	100RB+100RB:	37M6G7D;37M6W7D; 37M6W7D		
(Note: the necessary		100RB+50RB	27M7G7D;27M6W7D; 27M6W7D		
bandwidth of which is the worst value from the	LTE CA_7C	100RB+100RB	37M4G7D;37M5W7D; 37M6W7D		
measured occupied	LTE CA 38C	75RB+75RB	28M4G7D;28M4W7D; 28M4W7D		
bandwidths for each type of channel bandwidth	LIE CA_36C	100RB+100RB	37M7G7D;37M6W7D; 37M5W7D		
configuration.)	LTE CA 41C	75RB+75RB	28M4G7D;28M4W7D; 28M4W7D		
	LIE CA_4IC	100RB+100RB	37M7G7D;37M6W7D; 37M5W7D		



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5 Description of Tests

5.1 Conducted Output Power

Measurement Procedure: FCC KDB 971168 D01 Power Meas License Digital Systems v03

The transmitter output was connected to a calibrated coaxial cable, attenuator and power meter, the other end of which was connected to a Base Station Simulator. The Base Station Simulator was set to force the EUT to its maximum power setting. The power output at the transmitter antenna port was determined by adding the value of the cable insertion loss to the power reading. The tests were performed at three frequencies (low channel, middle channel and high channel) and on the highest power levels, which can be setup on the transmitters.

Note: Reference test setup 1

5.2 Effective (Isotropic) Radiated Power of Transmitter

Measurement Procedure: FCC KDB 971168 D01 Power Meas License Digital Systems v03

Below 1GHz test procedure as below:

- 1). The EUT was powered ON and placed on a 1.5m high table in the chamber. The antenna of the transmitter was extended to its maximum length.
- 2). The disturbance of the transmitter was maximized on the test receiver display by raising and lowering from 1m to 4m the receive antenna and by rotating through 360° the turntable. After the fundamental emission was maximized, a field strength measurement was made.
- 3). Steps 1) and 2) were performed with the EUT and the receive antenna in both vertical and horizontal polarization.
- 4). The transmitter was then removed and replaced with another antenna. The center of the antenna was approximately at the same location as the center of the transmitter.
- 5). A signal at the disturbance was fed to the substitution antenna by means of a non-radiating cable. With both the substitution and the receive antennas horizontally polarized, the receive antenna was raised and lowered to obtain a maximum reading at the test receiver. The level of the signal generator was adjusted until the measured field strength level in step 2) is obtained for this set of conditions.
- 6). The output power into the substitution antenna was then measured.
- 7). Steps 5) and 6) were repeated with both antennas polarized.
- 8). Calculate power in dBm by the following formula:

```
ERP (dBm) = Pg(dBm) - cable loss (dB) + antenna gain (dBd)
```

Where:

Pg is the generator output power into the substitution antenna.

Above 1GHz test procedure as below:

- 1). Different between above is the test site, change from Semi- Anechoic Chamber to fully Anechoic Chamber
- 2). Calculate power in dBm by the following formula:

EIRP(dBm) = Pg(dBm) - cable loss (dB) + antenna gain (dBi)

EIRP=ERP+2.15dB

Where:

Pg is the generator output power into the substitution antenna.

- 3). Test the EUT in the lowest channel, the middle channel the Highest channel
- 4). The radiation measurements are performed in X, Y, Z axis positioning. And found the X axis positioning which it is worse case, Only the test worst case mode is recorded in the report.
- 5). Repeat above procedures until all frequencies measured was complete.

Note: Reference test setup 2

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5.3 Occupied Bandwidth

Measurement Procedure: FCC KDB 971168 D01 Power Meas License Digital Systems v03

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured. The transmitter output was connected to a calibrated coaxial cable, attenuator and Spectrum analyser, the other end of which was connected to a Base Station Simulator. The Base Station Simulator was set to force the EUT to its maximum power setting. The tests were performed at three frequencies (low channel, middle channel and high channel). The span of the analyzer shall be set to capture all products of the modulation process, including the emission skirts. The resolution bandwidth shall be set to as close to 1 percent of the selected span as is possible without being below 1 percent. The video bandwidth shall be set to 3 times the resolution bandwidth. Video averaging is not permitted. Where practical, a sampling detector shall be used since a peak or, peak hold, may produce a wider bandwidth than actual. The trace data points are recovered and are directly summed in linear terms. The recovered amplitude data points, beginning at the lowest frequency, are placed in a running sum until 0.5 percent of the total is reached and that frequency recorded. The process is repeated for the highest frequency data points. This frequency is recorded. The span between the two recorded frequencies is the occupied bandwidth.

Note: Reference test setup 1

5.4 Band Edge at Antenna Terminals

Measurement Procedure: FCC KDB 971168 D01 Power Meas License Digital Systems v03

The transmitter output was connected to a calibrated coaxial cable, attenuator and Spectrum analyser, the other end of which was connected to a Base Station Simulator. The Base Station Simulator was set to force the EUT to its maximum power setting. The tests were performed at three frequencies (low channel and high channel).in the 1MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of 100kHz or 1% of the emission bandwidth of the fundamental emission of the transmitter may be employed. The EUT emission bandwidth is measured as the width of the signal between two points, outside of which all emission are attenuated at least 26dB below the transmitter power. The video bandwidth of the spectrum analyzer was set at thrice the resolution bandwidth. Detector Mode was set to peak or peak hold power.

Note: Reference test setup 1

5.5 Spurious And Harmonic Emissions at Antenna Terminal

Measurement Procedure: FCC KDB 971168 D01 Power Meas License Digital Systems v03

The transmitter output was connected to a calibrated coaxial cable, attenuator and Spectrum analyzer, the other end of which was connected to a Base Station Simulator. The Base Station Simulator was set to force the EUT to its maximum power setting. The tests were performed at three frequencies (low channel and high channel). The level of the carrier and the various conducted spurious and harmonic frequencies is measured by means of a calibrated spectrum analyzer. The spectrum is scanned from the lowest frequency generated in the equipment up to a frequency including its 10th harmonic. On any frequency outside a licensee's frequency block, the power of any emission shall be attenuated below the transmitter power (P) by at least 43 + 10 log(P) dB. Compliance with these provisions is based on the use of measurement instrumentation employing a resolution bandwidth of 1 MHz or greater. However, in the 1 MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least one percent of the emission bandwidth of the fundamental emission of the transmitter may be employed. The emission bandwidth is defined as the width of the signal between two points, one below the carrier center frequency and one above the carrier center frequency, outside of which all emission are attenuated at least 26 dB below the transmitter power.

Note: Reference test setup 1

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5.6 Peak-Average Ratio

Measurement Procedure: FCC KDB 971168 D01 Power Meas License Digital Systems v03

A peak to average ratio measurement is performed at the conducted port of the EUT. For WCDMA signals, the spectrum analyzers Complementary Cumulative Distribution Function (CCDF) measurement profile is used to determine the largest deviation between the average and the peak power of the EUT in a given bandwidth. The CCDF curve shows how much time the peak waveform spends at or above a given average power level. The percent of time the signal spends at or above the level defines the probability for that particular power level. For GSM signals, an average and a peak trace are used on a spectrum analyzer to determine the largest deviation between the average and the peak power of the EUT in a bandwidth greater than the emission bandwidth. The traces are generated with the spectrum analyzer set to zero span mode.

Note: Reference test setup 1

5.7 Field Strength of Spurious Radiation

Measurement Procedure: FCC KDB 971168 D01 Power Meas License Digital Systems v03

Below 1GHz test procedure as below:

- 1). The EUT was powered ON and placed on a 150cm high table in the chamber. The antenna of the transmitter was extended to its maximum length.
- 2). The disturbance of the transmitter was maximized on the test receiver display by raising and lowering from 1m to 4m (for the test frequency of below 30MHz, the antenna was tuned to heights 1 meter) the receive antenna and by rotating through 360° the turntable. After the fundamental emission was maximized, a field strength measurement was made.
- 3). Steps 1) and 2) were performed with the EUT and the receive antenna in both vertical and horizontal polarization.
- 4). The transmitter was then removed and replaced with another antenna. The center of the antenna was approximately at the same location as the center of the transmitter.
- 5). A signal at the disturbance was fed to the substitution antenna by means of a non-radiating cable. With both the substitution and the receive antennas horizontally polarized, the receive antenna was raised and lowered to obtain a maximum reading at the test receiver. The level of the signal generator was adjusted until the measured field strength level in step 2) is obtained for this set of conditions.
- 6). The output power into the substitution antenna was then measured.
- 7). Steps 5) and 6) were repeated with both antennas polarized.
- 8) Calculate power in dBm by the following formula:

ERP(dBm) = Pg(dBm) - cable loss (dB) + antenna gain (dBd)

Where:

Pd is the dipole equivalent power, Pg is the generator output into the substitution antenna, and the antenna gain is the gain of the substitute antenna used relative to either a half-wave dipole (dBd) or an isotropic source (dBi). The substitute level is equal to Pg [dBm] – cable loss [dB]. The calculated Pd levels are then compared to the absolute spurious emission limit of -13dBm which is equivalent to the required minimum attenuation of 43 + 10log10(Power [Watts]).

Above 1GHz test procedure as below:

- 1) Different between above is the test site, change from Semi- Anechoic Chamber to fully Anechoic Chamber
- Calculate power in dBm by the following formula: EIRP(dBm) = Pg(dBm) - cable loss (dB) + antenna gain (dBi) EIRP=ERP+2.15dB

Where:

Pg is the generator output power into the substitution antenna.

- 3. Test the EUT in the lowest channel, the middle channel the Highest channel
- 4. The radiation measurements are performed in X, Y, Z axis positioning. And found the X axis positioning which it is worse case, Only the test worst case mode is recorded in the report.
- 5. Repeat above procedures until all frequencies measured was complete

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Note: Reference test setup 3

5.8 Frequency Stability / Temperature Variation

Measurement Procedure:

Frequency stability testing is performed in accordance with the guidelines of FCC KDB 971168 D01 Power Meas License Digital Systems v03

- . The frequency stability of the transmitter is measured by:
- a.) **Temperature:** The temperature is varied from -30 ℃ to +50 ℃ in 10 ℃ increments using an environmental chamber.
- b.) **Primary Supply Voltage:** The primary supply voltage is varied from 85% to 115% of the nominal value for non hand-carried battery and AC powered equipment. For hand-carried, battery-powered equipment, primary supply voltage is reduced to the battery operating end point which shall be specified by the manufacturer.

Specification – The frequency stability shall be sufficient to ensure that the fundamental emission stays within the authorized frequency block. The frequency stability of the transmitter shall be maintained within $\pm 0.00025\%$ (± 2.5 ppm) of the center frequency.

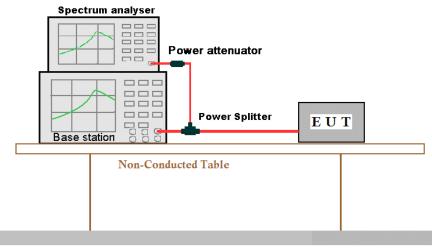
Time Period and Procedure:

- 1. The carrier frequency of the transmitter is measured at room temperature (20 °C to provide a reference).
- 2. The equipment is turned on in a "standby" condition for fifteen minutes before applying power to the transmitter. Measurement of the carrier frequency of the transmitter is made within one minute after applying power to the transmitter.
- 3. Frequency measurements are made at 10°C intervals ranging from -30°C to +50°C. A period of at least one half-hour is provided to allow stabilization of the equipment at each temperature level.

Note: Reference test setup 4

5.9 Test Setups

5.9.1 Test Setup 1



Ground Reference Plane



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5.9.2 Test Setup 2

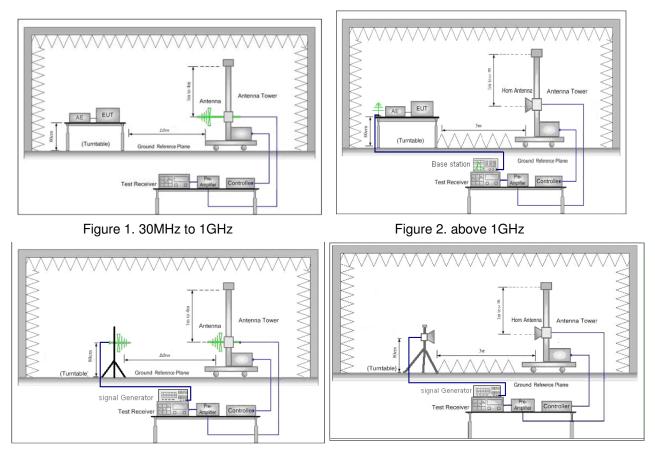


Figure 1. 30MHz to 1GHz

Figure 2. above 1GHz



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5.9.3 Test Setup 3

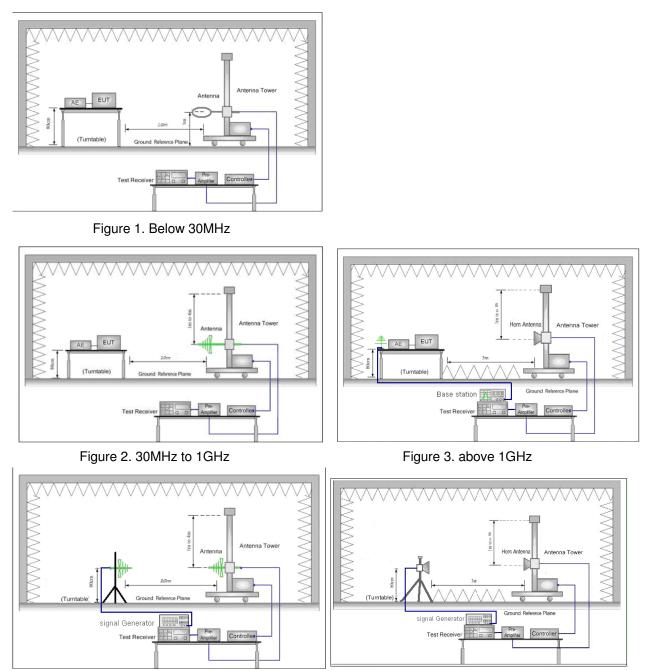


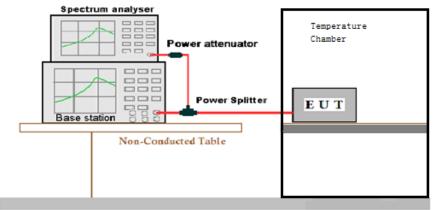


Figure 3. above 1GHz



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5.9.4 Test Setup 4



Ground Reference Plane



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Test Case		Test Conditions					
		Test Environment	Ambient Climate & Rated Voltage				
	Average	Test Setup	Test Setup 1				
	Power, Total	DE Channele (TV)	L, M, H				
Transmit		RF Channels (TX)	(L= low channel, M= middle channel, H= high channel)				
Output		Test Mode	LTE/TM1; LTE/TM2;LTE/TM3				
Power Data	Average	Test Environment	Ambient Climate & Rated Voltage				
Dala	Power,	Test Setup	Test Setup 1				
	Spectral Density (if	RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)				
	required)	Test Mode	LTE/TM1; LTE/TM2;LTE/TM3				
		Test Environment	Ambient Climate & Rated Voltage				
Peak-to-Av	erage Ratio	Test Setup	Test Setup 1				
(if required)	Ũ	RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)				
		Test Mode	LTE/TM1; LTE/TM2;LTE/TM3				
		Test Environment	Ambient Climate & Rated Voltage				
Modulation		Test Setup	Test Setup 1				
Characteris	tics	RF Channels (TX)	M (M= middle channel)				
		Test Mode	LTE/TM1;LTE/TM2;LTE/TM3				
	Occupied Bandwidth	Test Environment	Ambient Climate & Rated Voltage				
		Test Setup	Test Setup 1				
		RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)				
Bandwidth		Test Mode	LTE/TM1; LTE/TM2;LTE/TM3				
Danuwiutin	_ · ·	Test Environment	Ambient Climate & Rated Voltage				
	Emission Bandwidth	Test Setup	Test Setup 1				
	(if required)	RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)				
	roquirou)	Test Mode	LTE/TM1; LTE/TM2;LTE/TM3				
		Test Environment	Ambient Climate & Rated Voltage				
Band Edge	S	Test Setup	Test Setup 1				
Compliance	;	RF Channels (TX)	L, H (L= low channel, H= high channel)				
		Test Mode	LTE/TM1; LTE/TM2;LTE/TM3				
		Test Environment	Ambient Climate & Rated Voltage				
Spurious Er	mission at	Test Setup	Test Setup 1				
Antenna Te		RF Channels (TX)	L,M, H (L= low channel, M= middle channel, H= high channel)				
		Test Mode	LTE/TM1				
		Test Environment	Ambient Climate & Rated Voltage				
Field Streng Spurious Ra		Test Setup	Test Setup 2				
590.100011		Test Mode	LTE/TM1;LTE/TM2; LTE/TM3;NOTE: If applicable, the				

5.10 Test Conditions



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		EUT conf. that has maximum power density (based on the equivalent power level) is selected.				
		L, M, H				
	RF Channels (TX)	(L= low channel, M= middle channel, H= high channel)				
	Teet Env	(1) -30 ℃ to +50 ℃ with step 10 ℃ at Rated Voltage;				
	Test Env.	(2) VL, VN and VH of Rated Voltage at Ambient Climate.				
Eroguopov Stability	Test Setup	Test Setup 4				
Frequency Stability	RF Channels (TX)	L, M, H				
	nr Ghanneis (TA)	(L= low channel, M= middle channel, H= high channel)				
	Test Mode	LTE/TM1;LTE/TM2; LTE/TM3				



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6 Main Test Instruments

	RE in Chamber										
Item	Test Equipment	Manufacturer	Model No.	Inventory No.	Cal. date (yyyy-mm-dd)	Cal.Due date (yyyy-mm-dd)					
1	3m Semi-Anechoic Chamber	ETS-LINDGREN	N/A	SEM001-01	2017/5/10	2018/5/10					
2	EMI Test Receiver	Agilent Technologies	N9038A	SEM004-05	2017/10/9	2018/10/9					
3	BiConiLog Antenna (26-3000MHz)	ETS-LINDGREN	3142C	SEM003-02	201711-15	2020/11/15					
4	Double-ridged horn (1-18GHz)	ETS-LINDGREN	3117	SEM003-11	2015/10/17	2018/10/17					
5	Horn Antenna (18- 26GHz)	ETS-LINDGREN	3160	SEM003-12	2017/11/24	2020/11/24					
6	Pre-amplifier (0.1- 1300MHz)	Agilent Technologies	8447D	SEM005-01	2017/4/14	2018/4/14					
7	Pre-Amplifier (0.1- 26.5GHz)	Compliance Directions Systems Inc.	PAP-0126	SEM004-10	2017/10/17	2018/10/17					
8	Band filter	Amindeon	82346	SEM023-01	N/A	N/A					
9	Universal radio communication tester	Rohde &Schwarz	CMU200	SEM010-01	2017/10/9	2018/10/9					
10	Universal radio communication tester	Rohde &Schwarz	CMW500	SEM010-03	2017/10/23	2018/10/23					
11	DC Power Supply	Zhao Xin	RXN-305D	SEM011-02	2017/10/9	2018/10/9					
12	BiConiLog Antenna (30MHz-3GHz)	Schwarzbeck	VULB9163	SEM003-05	2015/10/17	2018/10/17					
13	Horn Antenna (800MHz-18GHz)	Rohde &Schwarz	HF907	SEM003-06	2015/6/14	2018/6/14					



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RE in Chamber								
Item	Test Equipment	Manufacturer	Model No.	Inventory No.	Cal. Date (yyyy mm-dd)	Cal. Due date (yyyy-mm-dd)		
1	10m Semi-Anechoic Chamber	SAEMC	FSAC1018	SEM001-03	2017/5/10	2018/5/10		
2	EMI Test Receiver (9k-7GHz)	Rohde & Schwarz	ESR	SEM004-03	2017/4/14	2018/4/14		
3	Trilog-Broadband Antenna(30M-1GHz)	Schwarzbeck	VULB9168	SEM003-18	2016/6/29	2019/6/29		
4	Pre-amplifier	Sonoma Instrument Co	310N	SEM005-03	2017/7/6	2018/7/6		
5	.Loop Antenna	ETS-Lindgren	6502	SEM003-08	2015/8/14	2018/8/14		

RF conducted test							
Item	Test Equipment	Manufacturer	Model No.	Inventory No.	Cal. Date (yyyy-mm-dd)	Cal.Due date (yyyy-mm-dd)	
1	Humi/ Temp Indicator	MingGao	TH101B	W006-09	2018/3/13	2019/3/12	
2	Signal Analyzer	Rohde Schwarz	FSV	W005-02	2018/3/13	2019/3/12	
3	Barometer	ChangChun	DYM3	SEL0088	2017/5/24	2018/5/24	
4	Dual Output Mobile Communication DC Source	Agilent Technologies Inc	66319D	W009-02	2017/7/23	2018/7/23	
5	Digital Multimeter	Fluke	15B+	W055-01	2018/3/3	2019/3/3	
6	Wideband Radio Communication Tester	Rohde & Schwarz	CMW500	W005-02	2018/3/13	2019/3/12	
7	Wideband Radio CommunicationTester	Rohde & Schwarz	CMW500	W005-02	2018/3/13	2019/3/12	
8	Wideband Radio CommunicationTeste	Anristu	MT8821C	6201462742	2017/8/13	2018/8/12	



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7 Measurement Uncertainty

For a 95% confidence level (k = 2), the measurement expanded uncertainties for defined systems, in accordance with the recommendations of ISO 17025 as following:

Test Item	Extended Uncertainty	Data	
Transmit Output Power Data	Power [dBm]	U = 0.37 dB	
Bandwidth	Magnitude [%]	U = 0.2%	
Band Edge Compliance	Disturbance Power [dBm]	U = 2.0 dB	
Spurious Emissions, Conducted	Disturbance Power [dBm]	U = 2.0 dB	
		For 3 m Chamber:	
		U = 4.5 dB (30 MHz to 1GHz)	
Field Strength of Spurious	ERP [dBm]	U = 3.3 dB (above 1 GHz)	
Radiation		For 10 m Chamber:	
		U = 4.5 dB (30 MHz to 1GHz)	
		U = 3.2 dB (above 1 GHz)	
Frequency Stability	Frequency Accuracy [ppm]	U = 0.24 ppm	

8 Photographs - EUT Constructional Details

Refer to Appendix A - Photographs of EUT Constructional Details for SZEM1803001945RG.

The End